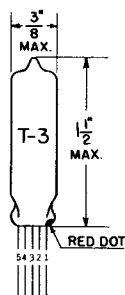


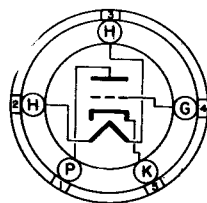
TUNG-SOL

TRIODE
SUBMINIATURE TYPE



HEATER

ANY MOUNTING POSITION



BOTTOM VIEW

0.046" TINNED FLEXIBLE LEADS
0.048" CENTER-TO-CENTER

GLASS BULB

DOT IS ADJACENT TO LEAD 1

THE 5744WB IS A HEATER-CATHODE TYPE HIGH-MU TRIODE OF SUBMINIATURE CONSTRUCTION CAPABLE OF OPERATION AS A FREQUENCY CONVERTER OR OSCILLATOR IN THE UHF REGION. IT IS ALSO USEFUL IN GENERAL PURPOSE AUDIO FREQUENCY VOLTAGE AMPLIFIER SERVICE. IT IS DESIGNED FOR SERVICE WHERE SEVERE CONDITIONS OF HIGH TEMPERATURE AND MECHANICAL SHOCK OR VIBRATION ARE ENCOUNTERED. THE FLEXIBLE TERMINAL LEADS MAY BE SOLDERED OR WELDED DIRECTLY TO THE TERMINALS OF CIRCUIT COMPONENTS WITHOUT THE USE OF SOCKETS. STANDARD INLINE SUBMINIATURE SOCKETS MAY BE USED BY CUTTING THE LEADS TO A SUITABLE LENGTH.

RATINGS

MECHANICAL

MAXIMUM IMPACT ACCELERATION (SHOCK TEST-NOTE 3)	450	G
MAXIMUM UNIFORM ACCELERATION (CENTRIFUGE TEST-NOTE 4)	1000	G
MAXIMUM VIBRATIONAL ACCELERATION (96 HR. FATIGUE-NOTE 5)	2.5	G
MAXIMUM BULB TEMPERATURE	220	°C

RATINGS AND NORMAL OPERATION

	MIL-E-1 SYMBOL	DES. MIN.	NORMAL TEST CONDITIONS NOTE 7	NORMAL OPERATION NOTE 6	DES. MAX.	MIL-E-1 UNITS
HEATER VOLTAGE (NOTE 8)	Ef:	5.7	6.3	6.3	6.9	VOLTS
PLATE VOLTAGE	Eb:	---	250	250	275	vdc
GRID #1 VOLTAGE	Ec1:	-55	0	0	---	vdc
PLATE DISSIPATION	Pp:	---	---	1.1	1.3	W
HEATER-CATHODE VOLTAGE	Ehk:	-200	---	100	+200	VOLTS
PLATE CURRENT	Ib:	---	---	4.2	6.5	mAdc
CATHODE RESISTANCE	Rk:	---	500	500	---	OHMS
GRID CIRCUIT RESISTANCE	Rg:	---	---	---	1.2	MEG OHMS
GRID CURRENT	Ic:	---	---	---	1.0	mAdc
TRANSCONDUCTANCE (1):	Sm(1):	---	---	4000	---	μMHOS
AMPLIFICATION FACTOR	Mu:	---	---	70	---	---

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CHARACTERISTICS AND QUALITY CONTROL TESTS¹

TEST	AQL %	MIL- E-1 SYM- BOL	MIN.	LAL	BOG.	UAL.	MAX.	ALD.	MIL-E-1 UNITS	
										COMBINED AQL = 1.0% EXCLUDING MECHANICAL AND INOPERATIVES
MEASUREMENTS ACCEPTANCE TESTS PART 1										
HEATER CURRENT:	0.65		1f:	190	---	200	---	210	---	mA
HEATER-CATHODE										
LEAKAGE: E _{hk} = -100Vdc;										
E _{hk} = +100 vdc	0.65		lhk:	---	---	---	---	5	---	μAdc
GRID CURRENT	0.65		lc(1):	---	---	---	---	-0.3	---	μAdc
PLATE CURRENT (1):	0.65		lb(1):	3.2	3.7	4.2	4.7	5.2	1.2	mAdc
PLATE CURRENT (2):										
E _{c1} = -6.5 vdc	0.65		lb(2):	---	---	---	---	50	---	μAdc
TRANSCONDUCTANCE (1):	0.65		S _{m(1)} :	3400	3700	4000	4300	4600	660	μMHOS
AC AMPLIFICATION:										
E _{sig} = 0.2 Vac;										
E _{bb} = 100 Vdc; E _{cc} = 0;										
R _{g1} = 10 MEG; R _k = 0;										
R _p = 0.5 MEG.	0.65		E _p :	6.5	---	---	---	---	---	Vac
CONTINUITY AND SHORTS (INOPERATIVES:)	0.4			---	---	---	---	---	---	---
MECHANICAL:										
ENVELOPE (8-7)				---	---	---	---	---	---	---
MEASUREMENTS ACCEPTANCE TESTS PART 2										
INSULATION OF										
ELECTRODES: E _f = 6.3V.										
E _g -all = -100 vdc	2.5		R _{g1} - all:	100	---	---	---	---	---	MEG.
E _p -all = -300 vdc	2.5		R _p - all:	100	---	---	---	---	---	MEG.
PLATE CURRENT (3)										
E _{c1} = -4.0 vdc	2.5		lb(3):	5	---	---	---	---	---	μAdc
TRANSCONDUCTANCE (2):										
E _f = 5.7 v.	2.5		ΔE _f / S _{m(2)} :	---	---	---	---	5	---	PERCENT
GRID EMISSION:										
E _f = 7.5V; R _g = 1.0MEG.										
PREHEAT 5 MINUTES AT										
E _{c1} = 0; TEST AT E _{c1} = -										
10 vdc	2.5		lc(2):	---	---	---	---	-0.4	---	μAdc
AF NOISE:										
E _{sig} = 50 mVac; R _g =										
1.0 MEG; R _p = 0.2MEG.	2.5		EB:	---	---	---	---	17	---	VU
AMPLIFICATION FACTOR	6.5		Mu:	60	65	70	75	80	7	---
CAPACITANCE:			C _{cap} :	0.65	---	0.8	---	0.95	---	μμf
CAPACITANCE: (NOTE 2)	6.5		C _{in} :	2.0	---	2.7	---	3.4	---	μμf
CAPACITANCE:			C _{out} :	1.6	---	2.3	---	3.0	---	μμf
LOW PRESSURE										
VOLTAGE BREAKDOWN:										
PRESSURE = 55±5 mm Hg:										
VOLTAGE = 300 Vac	6.5			---	---	---	---	---	---	---

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CHARACTERISTICS AND QUALITY CONTROL TESTS - cont'd.

TEST	AQL %	MIL-E-1 MIN SYMBOL	LAL	BOGIE	UAL	MAX	ALD	MIL-E-1 UNITS
MEASUREMENTS ACCEPTANCE TESTS PART 2 - cont'd.								

COMBINED AQL = 1.0% EXCLUDING MECHANICAL AND INOPERATIVES

OPERATION TIME (NOTE 10)	4.0	t:	---	---	---	20	---	SEC.
VIBRATION (2): F = 40 cps; G = 15; Rp = 10,000 OHMS	2.5	Ep:	---	---	---	15	---	mVac.
VIBRATION (3): Rp = 10,000 OHMS; F = 30 - 1000 cps; G = 15; POSITION X ₁ AND X ₂ ONLY.	4.0	ep:	---	---	---	75	---	mV
						PEAK TO PEAK		

DEGRADATION RATE ACCEPTANCE TESTS

SUBMINIATURE LEAD FATIGUE:	2.5	---	4.0	---	---	---	---	arcs
SHOCK (1): HAMMER ANGLE = 30°; Ehk = ±100 vdc; Rg1 = 0.1 MEG.; (NOTE 3)	20	---	---	---	---	---	---	---
FATIGUE (1): 96 HOURS; G = 2.5; FIXED FREQUENCY; F = 25 MIN. 60 MAX. (NOTE 5)	6.5	---	---	---	---	---	---	---
FATIGUE (2): 6 HOURS; G = 10; FIXED FREQUENCY; F = 25 MIN. 60 MAX. (NOTE 11)	6.5	---	---	---	---	---	---	---

ALLOWABLE DEFECTS PER CHARACTERISTIC
1st SAMPLE COMBINED SAMPLES

	AQL %	MIL-E-1 SYMBOL	MIN	MAX	MIL-E-1 UNITS
POST SHOCK (1) AND FATIGUE TESTS (1) AND (2) END POINTS; VIBRATION (2): F = 40 cps; G = 15; Rp = 10,000 OHMS	---	Ep:	---	25	mVac
HEATER-CATHODE LEAKAGE: Ehk = ± 100 vdc	---	lhk;	---	10	μAdc
CHANGE IN TRANSCONDUCTANCE (1) OF INDIVIDUAL TUBES; Ef = 6.3 VOLTS	---	Δ _t Sm(1):	---	10	PERCENT
GRID CURRENT (1):	---	lcl	---	-1.0	μAdc

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CHARACTERISTICS AND QUALITY CONTROL TESTS¹ - cont'd.

TEST	ALLOWABLE DEFECTS PER CHARACTERISTIC	AQL %	MIL-E-1 SYMBOL	MIN.	MAX.	MIL-E-1 UNITS
DEGRADATION RATE ACCEPTANCE TESTS - cont'd.	1st SAMPLE	COMBINED SAMPLES				
SHOCK (3): 75G; (HAMMER ANGLE= 120°+RUBBER PAD); t= 10 MILLISEC. (NOTE 12) Ehk =+100 Vdc; Rg1= 0.1 MEG.			20	---	---	---
POST SHOCK TEST (2) END POINTS: VIBRATION (2): F=40 cps; G=15; Rp = 10,000 OHMS			---	Ep:	---	25 mVac
HEATER-CATHODE LEAKAGE: Ehk=±100 Vdc			---	lhk:	---	10 μAde
CHANGE IN TRANSCON- DUCTANCE (1) OF IN- DIVIDUAL TUBES:; Ef =6.3 VOLTS			---	Δ ₁ Sm(1):	---	10 PERCENT
GRID CURRENT			---	lc:	---	-1.0 μAde
GLASS STRAIN (THERMAL SHOCK)			6.5	---	---	---
ACCEPTANCE LIFE TESTS						
HEATER CYCLING						
LIFE TEST: Ef = 7.5 V; Eb = Ec1 =0V; Ehk =140 Vac; 1 MIN. ON, 1 MIN. OFF						
			1.0	---	2000	---
HEATER CYCLING LIFE TEST END POINTS; HEATER-CATHODE LEAKAGE: Ehk =±100 Vdc						
			---	lhk:	---	20 μAde
1 HOUR STABILITY LIFE TEST: TA = ROOM; Ehk=+200 Vdc; Rg1 = 1.0 MEG.						
			---	---	---	---
1 HOUR STABILITY LIFE TEST END POINTS: CHANGE IN TRANSCON - DUCTANCE (1) OF INDIVIDUAL TUBES: (TYPICAL SAMPLE SIZE = 50 TUBES)						
			1.0	Δ ₁ Sm(1):	---	10 PERCENT
100 HOUR SURVIVAL RATE LIFE TEST: TA = ROOM; Ehk=+200 Vdc; Rg1 = 1.0 MEG.						
			---	---	---	---

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CHARACTERISTICS AND QUALITY CONTROL TESTS¹ - cont'd.

TEST	ALLOWABLE DEFECTS PER CHARACTERISTIC		AQL %	MIL-E-1 SYMBOL	MIN.	MAX.	MIL-E-1 UNITS
	1st SAMPLE	COMBINED SAMPLES					
ACCEPTANCE LIFE TEST - cont'd.							
100 HOUR SURVIVAL RATE			---	---	---	---	---
LIFE TEST END POINTS:							
(TYPICAL SAMPLE SIZE = 200 TUBES)							
INOPERATIVES:			0.65	---	---	---	---
TRANSCONDUCTANCE (1):			1.0	Sm(1):	3800	---	μMHOS
INTERMITTENT HIGH TEMPERATURE LIFE TEST:							
T BULB = 220 °C; Ehk = +200 Vdc; Rg = 1.0 MEG.			---	---	---	---	---
500 HOUR INTERMITTENT HIGH TEMPERATURE LIFE TEST END POINTS:							
(TYPICAL SAMPLE SIZE = 20 TUBES 1st SAMPLE, 40 TUBES 2nd SAMPLE)							
INOPERATIVES:	1	3	---	---	---	---	---
GRID CURRENT (1):	1	3	---	Ic(1):	---	-0.6	μAdc
HEATER CURRENT:	1	3	---	If:	180	220	mA.
CHANGE IN TRANSCONDUCTANCE (1) OF INDIVIDUAL TUBES:	1	3	---	Δ _t Sm(1):	---	20	PERCENT
TRANSCONDUCTANCE (2): (NOTE 9)	2	5	---	Δ _{E_t} Sm(2):	---	15	PERCENT
HEATER-CATHODE LEAKAGE: Ehk = ±100 Vdc	2	5	---	Ihk:	---	10	μAdc
INSULATION OF ELECTRODES:							
g1 - all	2	5	---	Rg1-all:	50	---	MEG.
p- all	2	5	---	Rp-all:	50	---	MEG.
TRANSCONDUCTANCE (1) AVERAGE CHANGE:	---	---	---	Avg. Δ _t Sm(1):	---	15	PERCENT
TOTAL DEFECTIVES:	4	8	---	---	---	---	---
1000 HOUR INTERMITTENT HIGH TEMPERATURE LIFE TEST END POINTS:							
(TYPICAL SAMPLE SIZE = 20 TUBES 1st SAMPLE, 40 TUBES 2nd SAMPLE)							
INOPERATIVES:	2	5	---	---	---	---	---
GRID CURRENT (1):	2	5	---	Ic(1):	---	-1.0	μAdc
HEATER CURRENT:	2	5	---	If:	177	223	mA
CHANGE IN TRANSCONDUCTANCE (1) OF INDIVIDUAL TUBES:	2	5	---	Δ _t Sm(1):	---	30	PERCENT
HEATER-CATHODE LEAKAGE: Ehk = ±100 Vdc	2	5	---	Ihk:	---	15	μAdc
TOTAL DEFECTIVES:	5	10	---	---	---	---	---

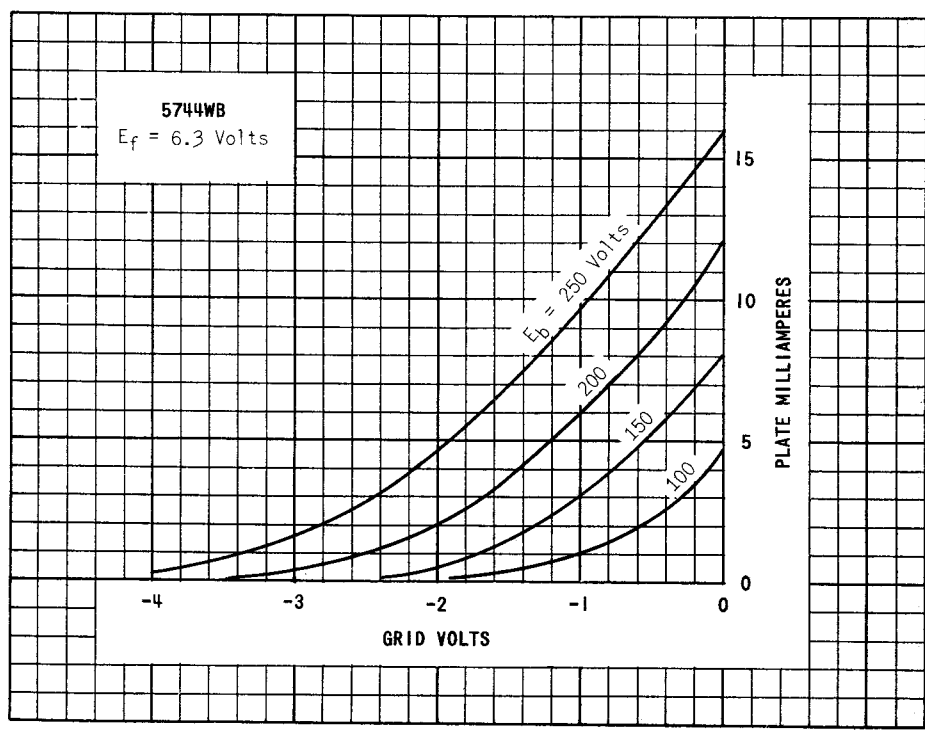
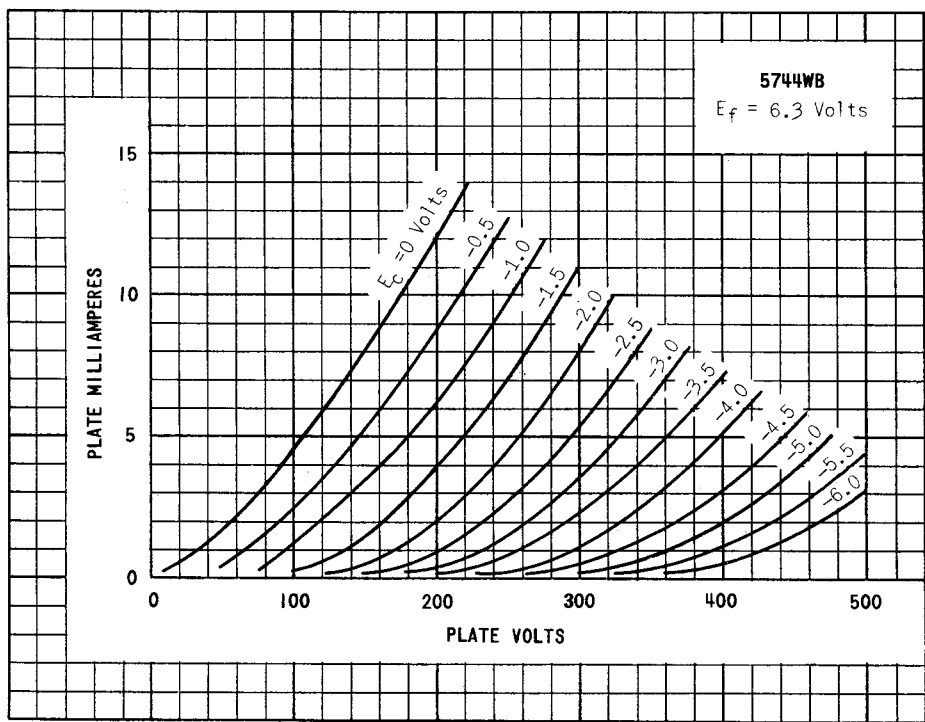
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NOTES

- ¹CHARACTERISTICS, QUALITY CONTROL TEST PROCEDURES, AND INSPECTION LEVELS ARE MADE ACCORDING TO THE APPROPRIATE PARAGRAPHS OF MIL-E-1 "INSPECTION INSTRUCTIONS FOR ELECTRON TUBES," AND MIL-STD-105A.
- ²WITH A CYLINDRICAL SHIELD (0.405" I.O.-1 7/8" LONG) CONNECTED TO LEAD 5.
- ³TEST CONDITIONS AND ACCEPTANCE CRITERIA PER SHOCK TEST PROCEDURES OF MIL-E-1 BASIC SPECIFICATIONS.
- ⁴CENTRIFUGE TEST WITH FORCES APPLIED IN ANY DIRECTION.
- ⁵TEST CONDITIONS AND ACCEPTANCE CRITERIA PER FATIGUE TEST PROCEDURES OF MIL-E-1 BASIC SPECIFICATIONS.
- ⁶THESE NORMAL VALUES REPRESENT CONDITIONS AT WHICH CONTROL OF RELIABILITY MAY BE EXPECTED.
- ⁷THESE NORMAL TEST CONDITIONS ARE USED FOR ALL CHARACTERISTICS TESTS UNLESS OTHERWISE STATED UNDER THE INDIVIDUAL TEST ITEM.
- ⁸FOR MOST APPLICATIONS THE PERFORMANCE WILL NOT BE ADVERSELY AFFECTED BY $\pm 10\%$ HEATER VOLTAGE VARIATION, BUT WHEN THE APPLICATION CAN PROVIDE A CLOSER CONTROL OF HEATER VOLTAGE, AN IMPROVEMENT IN RELIABILITY WILL BE REALIZED.
- ⁹CHANGE OF TRANSCONDUCTANCE FOR INDIVIDUAL TUBES FROM THAT VALUE MEASURED AT $E_f = 6.3$ V TO THAT VALUE MEASURED AT $E_f = 5.7$ V.
- ¹⁰OPERATION TIME IS THE TIME IN SECONDS REQUIRED FOR THE PLATE CURRENT TO ATTAIN A VALUE WITHIN PLUS OR MINUS 10% OF THE THREE MINUTE PLATE CURRENT (1) VALUE. NO PREHEATING BEFORE THIS TEST WILL BE ALLOWED.
- ¹¹THE TUBES SHALL BE RIGIDLY MOUNTED ON A TABLE VIBRATING WITH SIMPLE HARMONIC MOTION. THE TUBES SHALL BE VIBRATED FOR A TOTAL OF 6 HRS, 2 HRS. IN EACH OF THREE POSITIONS, X1, X2, Y1. ONLY RATED HEATER VOLTAGE SHALL BE APPLIED. TUBES WHICH SHOW ONE OR MORE OF THE FOLLOWING DEFECTS SHALL BE CONSIDERED FAILURES:
- (A) TUBES WHICH SHOW PERMANENT OR TAP SHORTS OR OPEN CIRCUITS FOLLOWING FATIGUE TEST, WHEN TESTED AS SPECIFIED IN PARAGRAPH 4.7.2 AND 4.7.3 OF SPECIFICATION MIL-E-1.
 - (B) TUBES WHICH DO NOT COMPLY WITH POST FATIGUE LIMITS. THIS IS DESTRUCTIVE TEST.
- ¹²THE PROVISIONS OF PARAGRAPH 4.9.20.5 OF SPECIFICATION MIL-E-1 SHALL APPLY, EXCEPT FOR TEST CONDITIONS LISTED FOR SHOCK TEST (2).



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